

P17997.A06



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : S. WAKASHIRO et al.

Group Art Unit: 2877

Serial No : 09/407,855

Examiner: Sang Nguyen

Filed : September 29, 1999

Confirmation No.: 3303

For : TARGET FOR PHOTOGRAMMETRIC ANALYTICAL MEASUREMENT
SYSTEM

REPLY UNDER 37 C.F.R. § 1.111

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In response to the Official Action of April 24, 2003, in which a three-month shortened statutory period for response was set to expire on July 24, 2003, and which has been extended to expire on August 25, 2003 (August 24, 2003, falling on a Sunday), by the enclosed Request for Extension of Time, Applicants respectfully request reconsideration and withdrawal of each of the outstanding rejections set forth in the above-mentioned Official Action together with consideration and allowance of all the claims pending herein, in due course.

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Drawings being on page 4 of this paper, including attached replacement sheets.

Remarks begin on page 5 of this paper.

An **Appendix** including amended drawing figures is attached following page 7 of this paper.

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